

September 2009

# TIL111M, TIL117M, MOC8100M General Purpose 6-Pin Phototransistor Optocouplers

#### **Features**

- UL recognized (File # E90700)
- VDE recognized (File #102497 for white package)Add option V (e.g., TIL111VM)

#### **Applications**

- Power supply regulators
- Digital logic inputs
- Microprocessor inputs
- Appliance sensor systems
- Industrial controls

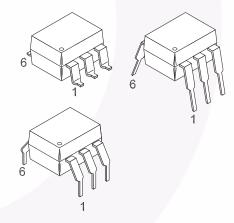
#### **General Description**

The MOC8100M, TIL111M and TIL117M optocouplers consist of a gallium arsenide infrared emitting diode driving a silicon phototransistor in a 6-pin dual in-line package.

#### **Schematic**

# ANODE 1 0 6 BASE CATHODE 2 0 5 COLLECTOR NC 3 0 4 EMITTER

# **Package Outlines**



#### **Absolute Maximum Ratings**

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter		Device	Value	Units
TOTAL DE	VICE				l
T <sub>STG</sub>	Storage Temperature		All	-40 to +150	°C
T <sub>OPR</sub>	Operating Temperature		All	-40 to +100	°C
T <sub>SOL</sub>	Lead Solder Temperature		All	260 for 10 sec	°C
P <sub>D</sub>	Total Device Power Dissipation @ T <sub>A</sub> = 25°C		All	250	mW
	Derate above 25°C			2.94	mW/°C
EMITTER		'			
I <sub>F</sub>	DC/Average Forward Input Current		All	60	mA
V <sub>R</sub>	Reverse Input Voltage		TIL111M	3	V
		МС	C8100M, TIL117M	6	
I <sub>F</sub> (pk)	Forward Current – Peak (300µs, 2% Duty Cycle)		All	3	А
$P_{D}$	LED Power Dissipation @ T <sub>A</sub> = 25 °C		All	120	mW
	Derate above 25°C			1.41	mW/°C
DETECTO	R				
V <sub>CEO</sub>	Collector-Emitter Voltage		All	30	V
V <sub>CBO</sub>	Collector-Base Voltage		All	70	V
V <sub>ECO</sub>	Emitter-Collector Voltage	Т	IL111M, TIL117M	7	V
V <sub>EBO</sub>	Emitter-Base Voltage		All	7	
P <sub>D</sub>	Detector Power Dissipation @ T <sub>A</sub> = 25 °C		All	150	mW
	Derate above 25°C			1.76	mW/°C

# **Electrical Characteristics** (T<sub>A</sub> = 25°C unless otherwise specified.)

# **Individual Component Characteristics**

Symbol	Parameter	Test Conditions		Device	Min.	Тур.*	Max.	Unit
EMITTER								
V <sub>F</sub>	Input Forward Voltage	I <sub>F</sub> = 16mA	T <sub>A</sub> = 25°C	TIL111M		1.2	1.4	V
		I <sub>F</sub> = 10mA for	$T_A = 0^{\circ}C - 70^{\circ}C$	MOC8100M,		1.2	1.4	
		MOC8100M,	T <sub>A</sub> = -55°C	TIL117M		1.32		
		I <sub>F</sub> = 16mA; for TIL117M	T <sub>A</sub> = +100°C			1.10		
I <sub>R</sub>	I <sub>R</sub> Reverse Leakage Current V <sub>R</sub> = 3.0V			TIL111M, TIL117M		0.001	10	μΑ
		V <sub>R</sub> = 6.0V		MOC8100M		0.001	10	μΑ
DETECTO	PR							
BV <sub>CEO</sub>	Collector-Emitter Breakdown Voltage	I <sub>C</sub> = 1.0mA, I <sub>F</sub> = 0		All	30	100		V
BV <sub>CBO</sub>	Collector-Base Breakdown Voltage	$I_{C} = 10\mu\text{A}, I_{F} = 0$		All	70	120		V
BV <sub>EBO</sub>	Emitter-Base Breakdown Voltage	$I_E = 10\mu A, I_F = 0$		All	7	10		V
BV <sub>ECO</sub>	Emitter-Collector Breakdown Voltage	I <sub>F</sub> = 100μA, I <sub>F</sub> = 0		TIL111M, TIL117M	7	10		V
I <sub>CEO</sub>	Collector-Emitter Dark	V <sub>CE</sub> = 10V, I <sub>F</sub> = 0	0	TIL111M, TIL117M		1	50	nA
	Current	$V_{CE} = 5V, T_A = 2$	5°C	MOC8100M		0.5	25	nA
		V <sub>CE</sub> = 30V, I <sub>F</sub> = 0, T <sub>A</sub> = 70°C		TIL117M, MOC8100M		0.2	50	μA
I <sub>CBO</sub>	Collector-Base Dark	V <sub>CB</sub> = 10V		TIL111M, TIL117M			20	nA
I <sub>CBO</sub>	Current	V <sub>CB</sub> = 5V		MOC8100M			10	nA
C <sub>CE</sub>	Capacitance	$V_{CF} = 0V, f = 1MHz$		All		8		pF

<sup>\*</sup>All Typical values at T<sub>A</sub> = 25°C

# **Electrical Characteristics** (Continued) (T<sub>A</sub> = 25°C unless otherwise specified.)

#### **Transfer Characteristics**

Symbol	Parameter	Test Conditions	Device	Min	Тур*	Max	Unit
DC CHAR	ACTERISTICS		•		•		
CTR <sub>CE</sub>	Current Transfer Ratio,	I <sub>F</sub> = 10mA, V <sub>CE</sub> = 10V TIL117M		50			%
	Collector to Emitter	I <sub>F</sub> = 1mA, V <sub>CE</sub> = 5V	MOC8100M	50			%
		I <sub>F</sub> = 1mA, V <sub>CE</sub> = 5V, T <sub>A</sub> = 0°C to +70°C		30			
I <sub>C(ON)</sub>	On-State Collector Current (Phototransistor Operation)	I <sub>F</sub> = 16mA, V <sub>CE</sub> = 0.4V	TIL111M	2			mA
	On-State Collector Current (Photodiode Operation)	I <sub>F</sub> = 16mA, V <sub>CB</sub> = 0.4V		7			μA
V <sub>CE (SAT)</sub>	Collector-Emitter Saturation Voltage	$I_C = 500\mu A, I_F = 10mA$	TIL117M			0.4	V
		I <sub>C</sub> = 2mA, I <sub>F</sub> = 16mA	TIL111M			0.4	
		$I_C = 100\mu A, I_F = 1mA$	MOC8100M		0.5		1
AC CHAR	ACTERISTICS				'		
T <sub>ON</sub>	Turn-On Time	$I_C = 2mA, V_{CC} = 10V,$ $R_L = 100\Omega$ (Fig. 11)	MOC8100M			20	μs
			TIL117M			10	
T <sub>OFF</sub>	Turn-Off Time		MOC8100M			20	μs
			TIL117M			10	
t <sub>r</sub>	Rise Time		MOC8100M	1	2		μs
t <sub>f</sub>	Fall Time		TIL117M		2		
t <sub>r</sub>	Rise Time (Phototransistor Operation)	$I_{C(ON)} = 2mA, V_{CC} = 10V,$ $R_L = 100\Omega$ (Fig. 11)	TIL111M			10	μs
t <sub>f</sub>	Fall Time (Phototransistor Operation)						

#### **Isolation Characteristics**

Symbol	Characteristic	Test Conditions	Min.	Тур.*	Max.	Units
V <sub>ISO</sub>	Input-Output Isolation Voltage	f = 60Hz, t = 1 sec.	7500			V <sub>AC(rms)</sub>
R <sub>ISO</sub>	Isolation Resistance	V <sub>I-O</sub> = 500 VDC	10 <sup>11</sup>			Ω
C <sub>ISO</sub>	Isolation Capacitance	$V_{I-O} = 0$ , $f = 1MHz$		0.2		pF

<sup>\*</sup>All Typical values at  $T_A = 25$ °C

# **Safety and Insulation Ratings**

As per IEC 60747-5-2, this optocoupler is suitable for "safe electrical insulation" only within the safety limit data. Compliance with the safety ratings shall be ensured by means of protective circuits.

Symbol	Parameter		Тур.	Max.	Unit
	Installation Classifications per DIN VDE 0110/1.89 Table 1				
	For Rated Main Voltage < 150Vrms		I-IV		
	For Rated Main voltage < 300Vrms		I-IV		
	Climatic Classification		55/100/21		
	Pollution Degree (DIN VDE 0110/1.89)		2		
CTI	Comparative Tracking Index	175			
V <sub>PR</sub>	Input to Output Test Voltage, Method b, V <sub>IORM</sub> x 1.875 = V <sub>PR</sub> , 100% Production Test with tm = 1 sec, Partial Discharge < 5pC	1594			V <sub>peak</sub>
	Input to Output Test Voltage, Method a, V <sub>IORM</sub> x 1.5 = V <sub>PR</sub> , Type and Sample Test with tm = 60 sec, Partial Discharge < 5pC	1275			V <sub>peak</sub>
V <sub>IORM</sub>	Max. Working Insulation Voltage	850			V <sub>peak</sub>
$V_{IOTM}$	Highest Allowable Over Voltage	6000			V <sub>peak</sub>
	External Creepage	7			mm
	External Clearance	7	1		mm
	Insulation Thickness	0.5			mm
RIO	Insulation Resistance at Ts, V <sub>IO</sub> = 500V	10 <sup>9</sup>			Ω

# **Typical Performance Characteristics**

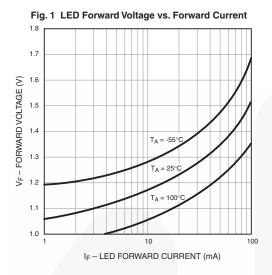


Fig. 3 Normalized CTR vs. Ambient Temperature

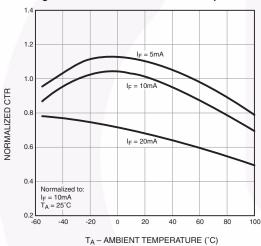


Fig. 5 CTR vs. RBE (Saturated)

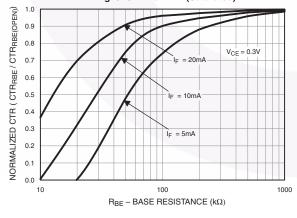


Fig. 2 Normalized CTR vs. Forward Current

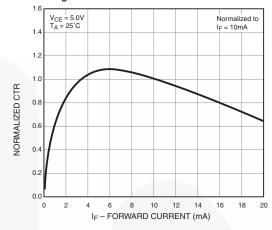


Fig. 4 CTR vs. RBE (Unsaturated)

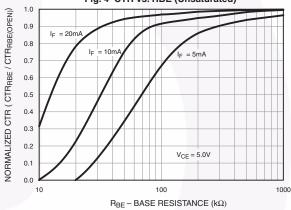
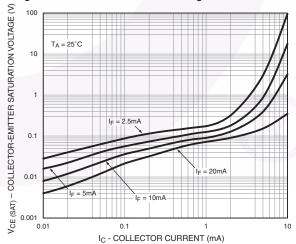


Fig. 6 Collector-Emitter Saturation Voltage vs Collector Current



# **Typical Performance Characteristics** (Continued)

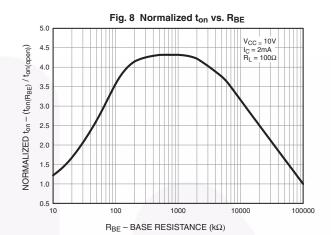
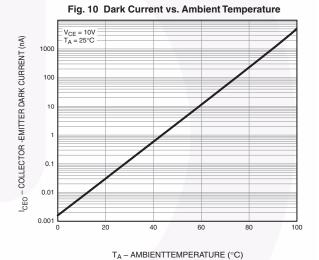
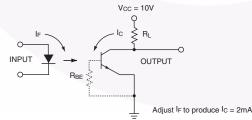


Fig. 9 Normalized toff vs. RBE 1.4 1.3  $\mathsf{NORMALIZED}\ t_{\mathsf{off}} - (t_{\mathsf{off}(\mathsf{RBE})}\ /\ t_{\mathsf{off}(\mathsf{open})})$ 1.2 1.1 1.0 0.9 0.8 0.7 0.6 0.5  $V_{CC} = 10V$   $I_{C} = 2mA$   $R_{L} = 100\Omega$ 0.4 0.3 0.2 0.1 10 100 1000 100000  $R_{BE}$  – BASE RESISTANCE (k $\Omega$ )



# TEST CIRCUIT WAVEFORMS



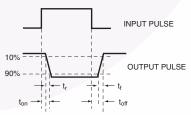
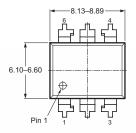
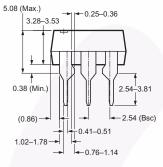


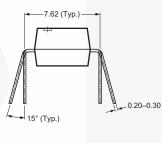
Figure 11. Switching Time Test Circuit and Waveforms

# **Package Dimensions**

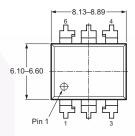
#### **Through Hole**

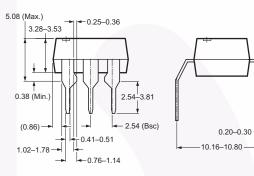




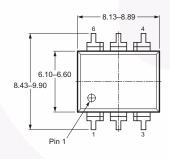


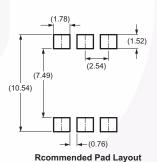
#### 0.4" Lead Spacing

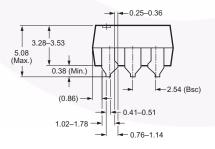


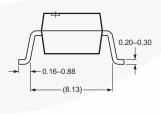


#### **Surface Mount**







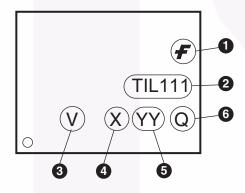


**Note:** All dimensions in mm.

# **Ordering Information**

Option	Order Entry Identifier (Example)	Description
No option	TIL111M	Standard Through Hole Device
S	TIL111SM	Surface Mount Lead Bend
SR2	TIL111SR2M	Surface Mount; Tape and Reel
Т	TIL111TM	0.4" Lead Spacing
V	TIL111VM	VDE 0884
TV	TIL111TVM	VDE 0884, 0.4" Lead Spacing
SV	TIL111SVM	VDE 0884, Surface Mount
SR2V	TIL111SR2VM	VDE 0884, Surface Mount, Tape and Reel

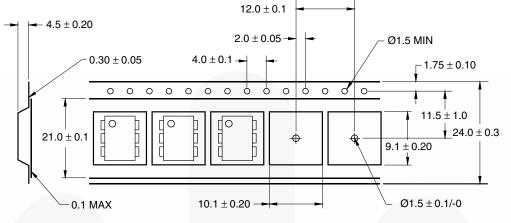
# **Marking Information**



Definitions					
1	Fairchild logo				
2	Device number				
3	VDE mark (Note: Only appears on parts ordered with VDE option – See order entry table)				
4	One digit year code, e.g., '7'				
5	Two digit work week ranging from '01' to '53'				
6	Assembly package code				

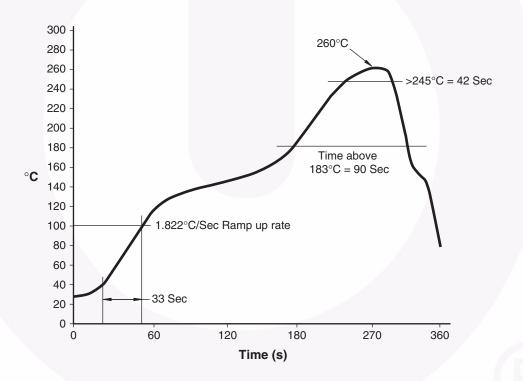
<sup>\*</sup>Note – Parts that do not have the 'V' option (see definition 3 above) that are marked with date code '325' or earlier are marked in portrait format.

# **Carrier Tape Specification**



User Direction of Feed ----

#### **Reflow Profile**







The Power Franchise®

bwer

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TinyBuck™

TinyLogic<sup>®</sup>

TINYOPTO™

TinyPower™

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#### **Definition of Terms**

Scinition of Terms						
<b>Datasheet Identification</b>	Product Status	Definition				
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.				
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.				
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.				
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.				

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